

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV.7-80) PATENT AND TRADEMARK OFFICE				Atty. Docket No. GB 000180		Serial No.	
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				Applicant PAUL F. FEWSTER et al.			
				Filing Date CONCURRENTLY		Group	

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 12/13/01

U.S. PATENT DOCUMENTS														
Ex. Int.		Document Number								Date	Name	Class	Sub-class	Filing Date If Approp.
	AA													
	AB													
	AC													
	AD													
	AE													
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FOREIGN PATENT DOCUMENTS															
		Document Number								Date	Country	Class	Sub-class	Trans.	
														Yes	No
ACH	AG	0	3	1	8	0	1	2	A 2	5/31/89	EUROPE	G01N	23/207	X	
ACH	AH	A	0	1	2	7	0	6	5 0	10/27/89	Japan (Abstract)	G01N	23/207	X	
ACH	AI	A	0	1	2	7	6	0	5 2	11/6/89	Japan (Abstract)	G01N	23/207	X	
	AJ														
	AK														

OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)	
ACH	AL "Characterization of Thin Layers on Perfect Crystals with a Multipurpose High Resolution X-ray Diffractometer", Bartels, Journal Vacuum Science and Technology B Volume 1 page 338 (1983). AM AN

Examiner <u>Allen C. Ho</u>	Date Considered <u>9/30/02</u>
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.